



SLOVENSKI STANDARD
SIST EN IEC 62132-8:2026

01-maj-2026

Nadomešča:
SIST EN 62132-8:2012

Integrirana vezja - Meritve elektromagnetne odpornosti - 8. del: Meritev odpornosti proti sevanju - Metoda z IC na tračnem valovodu (IEC 62132-8:2026)

Integrated circuits - Measurement of electromagnetic immunity - Part 8: Measurement of radiated immunity - IC stripline method (IEC 62132-8:2026)

Integrierte Schaltungen - Messung der elektromagnetischen Störfestigkeit - Teil 8: Messung der Störfestigkeit bei Einstrahlungen - IC-Streifenleiterverfahren (IEC 62132-8:2026)

Circuits intégrés - Mesure de l'immunité électromagnétique - Partie 8: Mesure de l'immunité rayonnée - Méthode de la ligne TEM à plaques pour circuit intégré (IEC 62132-8:2026)

Ta slovenski standard je istoveten z: EN IEC 62132-8:2026

ICS:

31.200	Integrirana vezja, mikroelektronika	Integrated circuits. Microelectronics
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EUROPEAN STANDARD
NORME EUROPÉENNE
EUROPÄISCHE NORM

EN IEC 62132-8

March 2026

ICS 31.200

Supersedes EN 62132-8:2012

English Version

**Integrated circuits - Measurement of electromagnetic immunity -
Part 8: Measurement of radiated immunity - IC stripline method
(IEC 62132-8:2026)**

Circuits intégrés - Mesure de l'immunité électromagnétique
- Partie 8: Mesure de l'immunité rayonnée - Méthode de la
ligne TEM à plaques pour circuit intégré
(IEC 62132-8:2026)

Integrierte Schaltungen - Messung der elektromagnetischen
Störfestigkeit - Teil 8: Messung der Störfestigkeit bei
Einstrahlungen - IC-Streifenleiterverfahren
(IEC 62132-8:2026)

This European Standard was approved by CENELEC on 2026-03-19. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

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Ref. No. EN IEC 62132-8:2026 E

EN IEC 62132-8:2026 (E)

European foreword

The text of document 47A/1205/FDIS, future edition 2 of IEC 62132-8, prepared by SC 47A "Integrated circuits" of IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 62132-8:2026.

The following dates are fixed:

- latest date by which the document has to be implemented at national (dop) 2027-03-31 level by publication of an identical national standard or by endorsement
- latest date by which the national standards conflicting with the (dow) 2029-03-31 document have to be withdrawn

This document supersedes EN 62132-8:2012 and all of its amendments and corrigenda (if any).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC shall not be held responsible for identifying any or all such patent rights.

This document is read in conjunction with EN 62132-1.

This document has been prepared under a standardization request addressed to CENELEC by the European Commission. The Standing Committee of the EFTA States subsequently approves these requests for its Member States.

Any feedback and questions on this document should be directed to the users' national committee. A complete listing of these bodies can be found on the CENELEC website.

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Endorsement notice

The text of the International Standard IEC 62132-8:2026 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following note has to be added for the standard indicated:

IEC 61000-4-20 NOTE Approved as EN IEC 61000-4-20

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cencenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050-131	-	International Electrotechnical Vocabulary - Part 131: Circuit theory	-	-
IEC 60050-161	-	International Electrotechnical Vocabulary. Chapter 161: Electromagnetic compatibility	-	-
IEC 62132-1	-	Integrated circuits - Measurement of electromagnetic immunity - Part 1: General conditions and definitions	EN 62132-1	-

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INTERNATIONAL STANDARD

**Integrated circuits - Measurement of electromagnetic immunity -
Part 8: Measurement of radiated immunity - IC stripline method**

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